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INFORMATION DISCLOSURE CITATION IN AN APPLICATION		APPLICANT Meral Bradley Woodberry				
		FILING DATE March 15, 2000		GROUP ART UNIT		
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	DATE IF APPROP
VN	5,047,711	09/10/91	Smith et al	724	158R	08/23/89
VN	4,968,931	11/06/90	Littlebury et al.	324	158R	11/03/89
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY/NAME	CLASS	SUB CLASS	TRANSLATION YES NO
OTHER DOCUMENTS						
VN	Article entitled, "Securing Known Good Die", by T. A. Williams, published in Advanced Packaging, Fall 1992, pp. 50-59					
VN	Article entitled, Known-Good Die Poised to Take Off", by D. Maliniak, published in Electronic Design, 11-21-94, pp. 55-73					
VN	Article entitled, "Burn-In Co-Developed by TI, MicroModule System, Intel Launches 'SmartDie' Program, by Jim Detar, published in Electronic News, May 30, 1994					
VN	Article entitled, "Known Good Die: A Commercial Solution for Burn-in and Test Before Packaging" by S-H Foo and L. Prokopchak, presented at Semicon Japan, 12-94					
VN	Article entitled, "Flexibility and Modularity Drive Today's Burn-In/Test Systems" by P. Mayerfeld, reprinted from EE-Evaluation Engineering, November 1994					
VN	Specification entitled, "Known Good Die - The Total Solution", AEIIR Test Systems/Nitto-Denko					
EXAMINER Vinh Nguyen			DATE CONSIDERED 10/09/03			

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